

Nissin Low-pressure Microwave Plasma System

Confidential information

Nissin Inc. Japan



-Outline-

- Company profile
- Plasma process
- Plasma application
- Plasma equipment

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The information should not present out of Nissin Inc.

Company Profile

Name: Nissin Inc. (<http://www.nissin-inc.co.jp>)

Establish: May/1947

Location: H.Q.

Takarazuka, Hyogo-pref. Japan

Yokohama sales center

Yokohama, Kanagawa pref. Japan

Yokohama R&D center

Yokohama, Kanagawa pref. Japan

Capital stock: 99,000,000 (JPY)

Employment: 200

Plasma business: R&D, design, manufacturing, and sales of plasma system


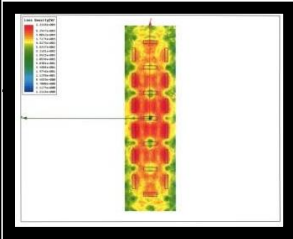
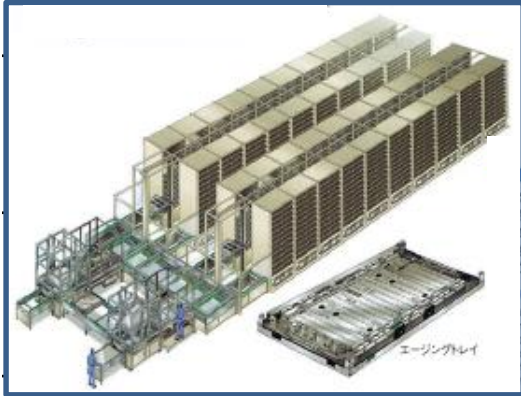

Main customers of plasma business:

Major package companies (Flip-chip, HDI, CSP) 、

Major PCB maker, Major FPC maker, Automotive etc.



Product history

Year	Microwave power source	Microwave Plasma R&D	Plasma measurent, diagnostics	Plasma process R&D	Mechatronics
1985	半導体メカ向け OEM開発・供給開始 				
1990					
1995	Start sales for plasma usage 1.5kW,3kW,6kW				
2000	Start sales for heating 6kW	Start R&D of plasma Develop plasma System for experiment	Develop plasma density Measurement method Start sales of Plasma density measurement probe	Establish R&D Center for plasma research	Start sales PDP aging system
2005					

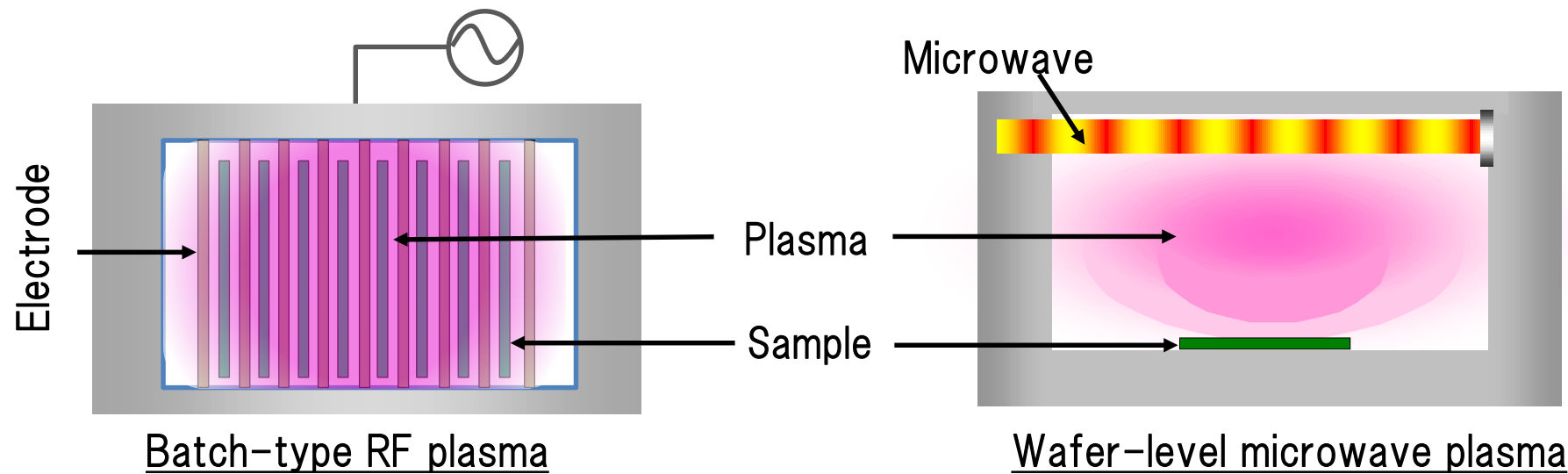
Enter plasma equipment market

Sales reord: more than 100systems

Process application: PCB, Packaging, surface modification,
resist stripping, reduction, improve adhesion

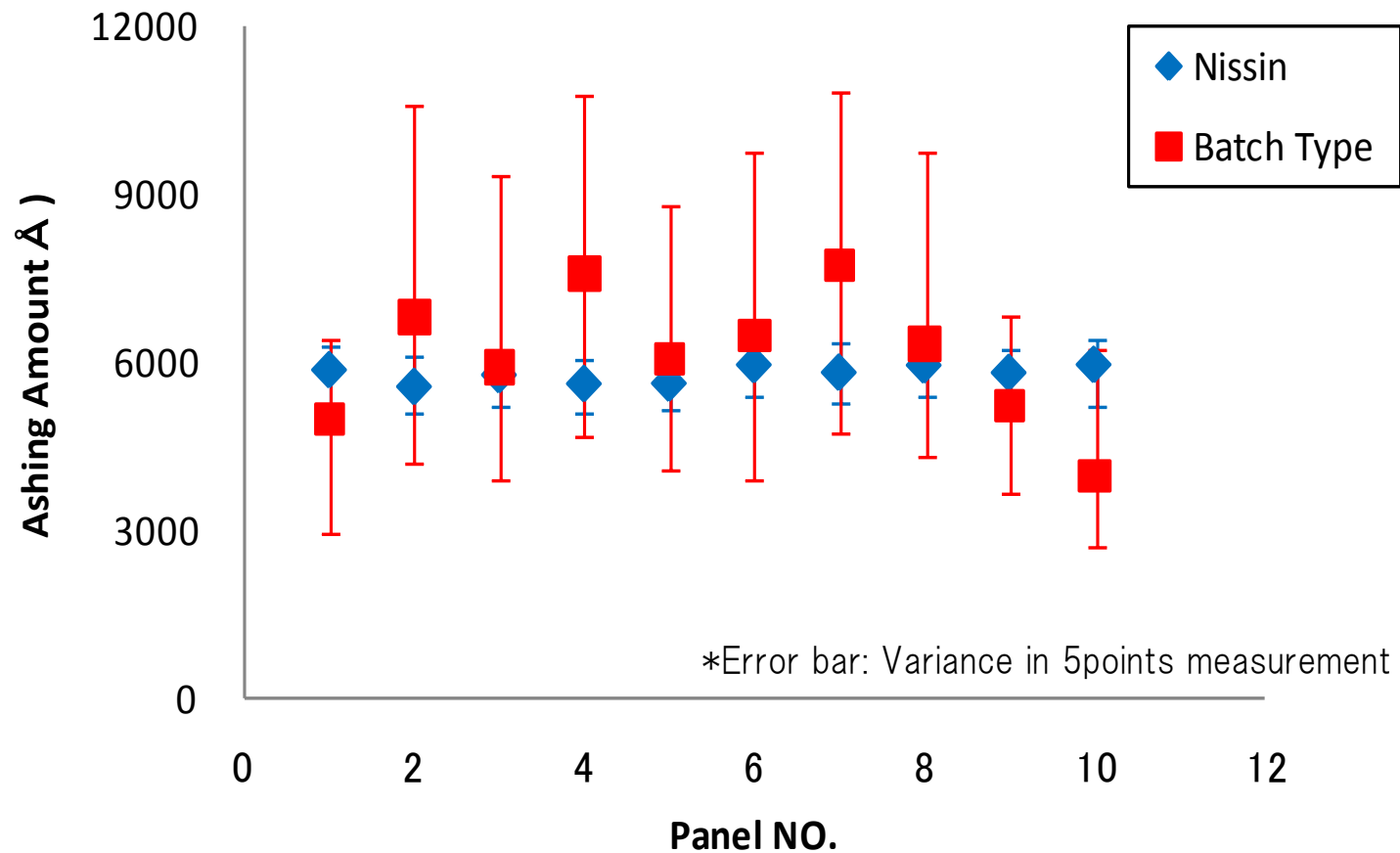
- **Low Pressure Microwave Plasma** Equipment
- **High power plasma** compared with RF plasma
- **Excellent processing uniformity**
- **Low temp.** process compared with RF plasma
- Available **full automation system**

Comparison of RF and Microwave Plasma



RF 13.56MHz	Source frequency	Microwave 2450MHz
About $10^9/\text{cm}^3$	Electron density	About $10^{12}/\text{cm}^3$
About 180°C	Processing temperature	Less than 90°C
High	Static damage	Low
Batch-type→Hard to automation In-plasma processing→High damage Plasma with electrodes→Low uniformity	Feature	Scanning process→High uniformity Remote plasma processing→Low damage Wafer-level processing→Easy to automation

Uniformity of Resist Stripping Rate

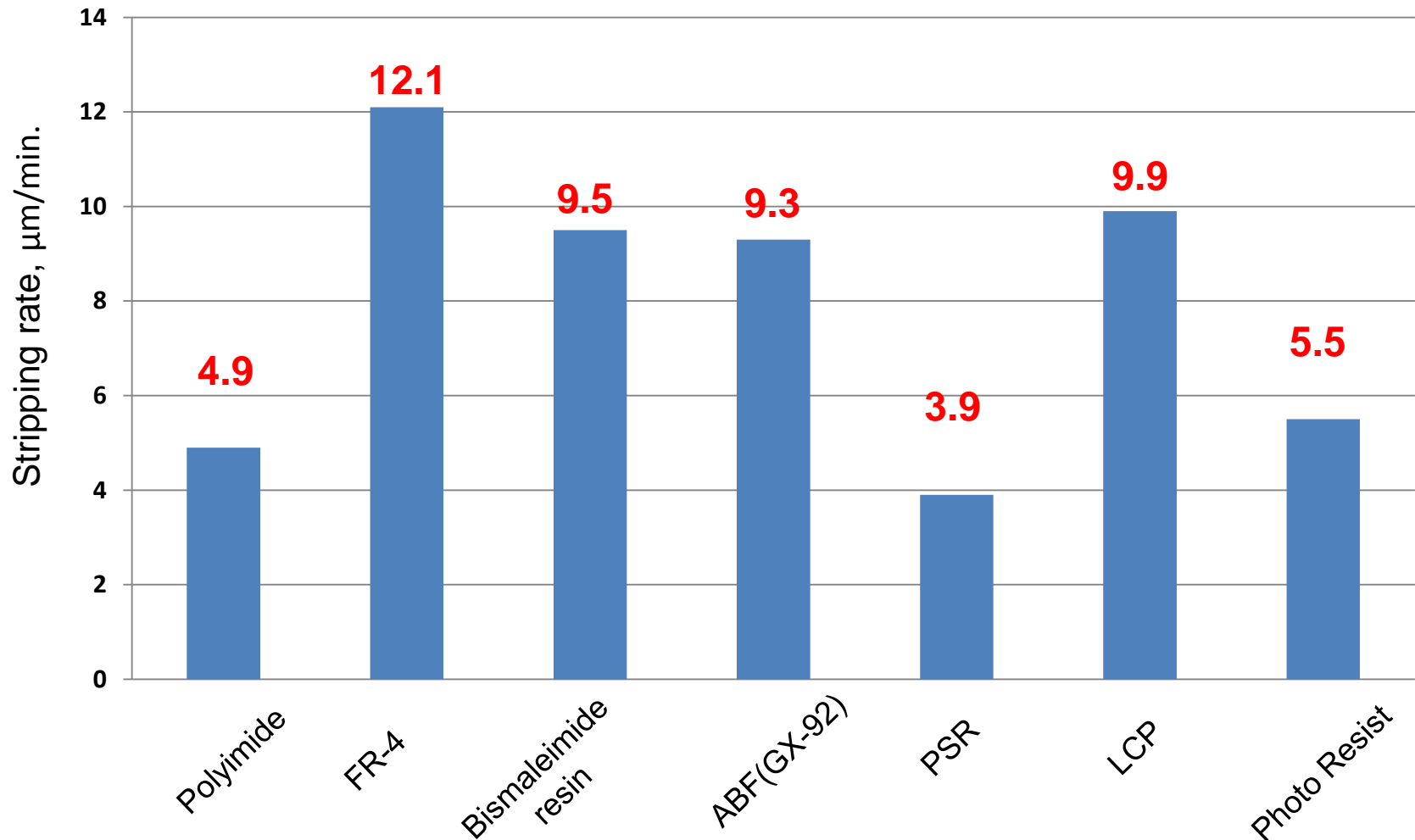


Uniformity of conventional RF plasma $\geq \pm 50\%$
Uniformity Nissin microwave plasma $\leq \pm 20\%$

Application: Organic material Etching (Etching rate)

Nissin Plasma Technology

Realizes high-speed stripping rate for organic materials by applying microwave plasma. Its stripping rate is **about 20 times larger than that of RF plasma**.



Nissin Plasma Technologies

Application: Improve Wettability (Contact Angle)

Nissin Plasma Technology

Nissin plasma can improve surface wettability of various materials with short plasma treatment time

Result

Contact angle measurement before and after 3sec. plasma treatment

	Before	After
PI	64°	5°
FR-4	78°	6°
SR	71°	11°
LCP	89°	12°
PMMA	81°	17°
PET	81°	5°
PS	82°	5°
Cu	84°	5°
SiO ₂	22°	5°



Application: Improve Peel Strength

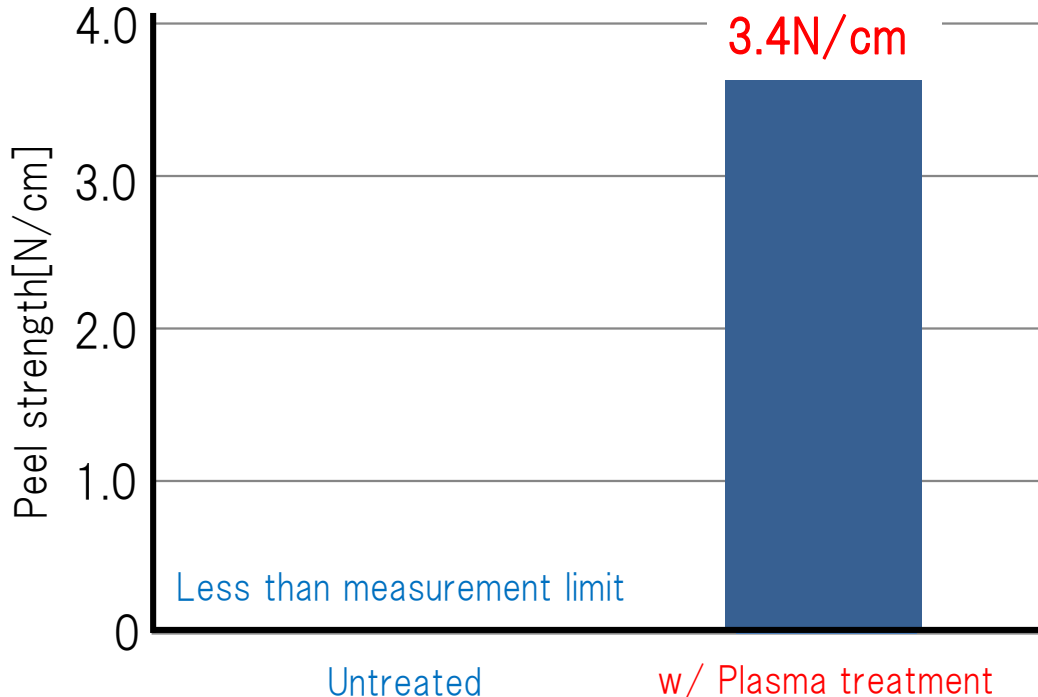
Application

Improve peel strength for the materials which has low surface profile, low surface energy, or hydrophobic.

Application example

Process: improve peel strength between **electroless Cu plating** and PTFE
 Treatment time: 10sec.
 Measurement: 180degree peel test

Result



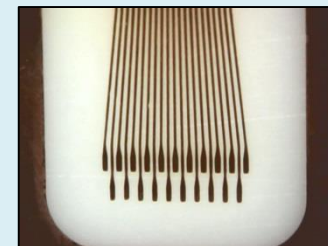
Untreated: Failed



Treated: OK



Patterning on PTFE; L/S=50/50μm



Application: Improve adhesion Strength

Application

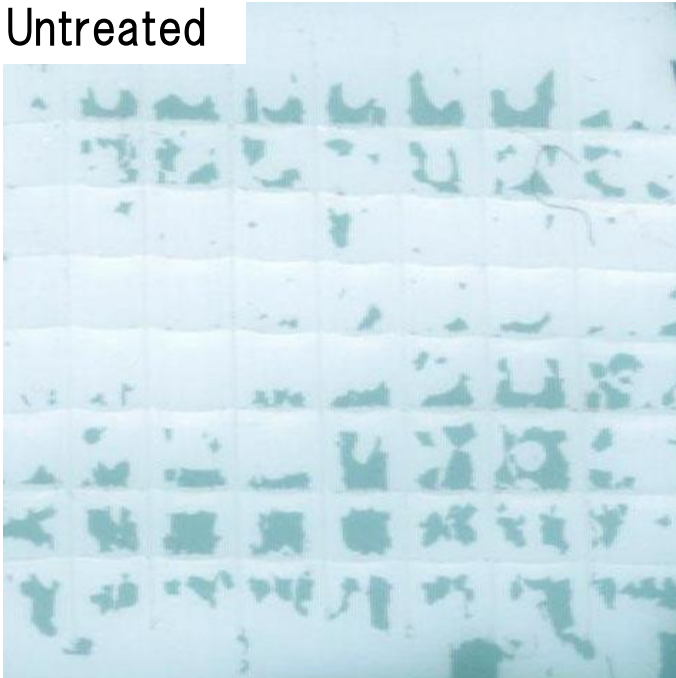
Improve adhesion strength for the materials which has low surface profile, low surface energy, or hydrophobic.

Application example

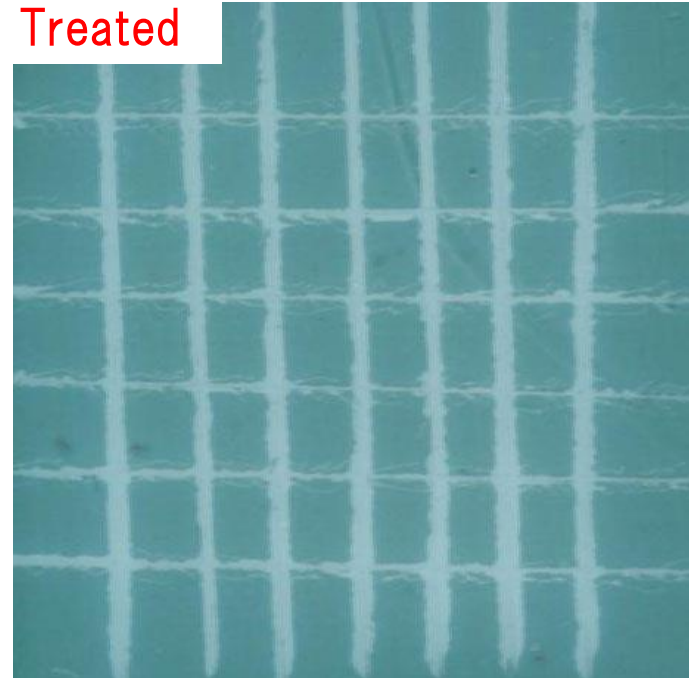
Process: improve peel strength between liquid photo resist and PTFE
 Treatment time: 10sec.
 Measurement: Cross-cut test checkerboard 1mm²

Result

Untreated

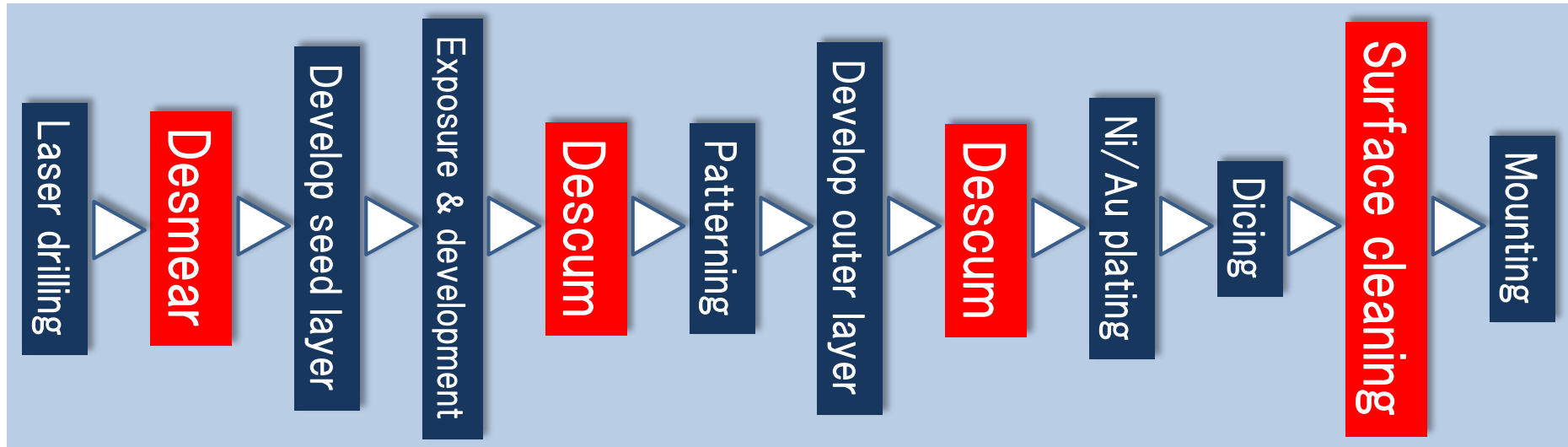


Treated



Plasma application for PCB and packaging

PCB application



Dry desmear

- Micro via
- High-aspect
- Hydrophobic materials

Fine-pitch patterning

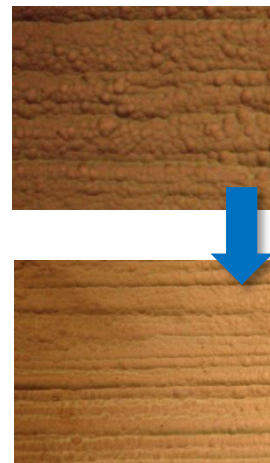
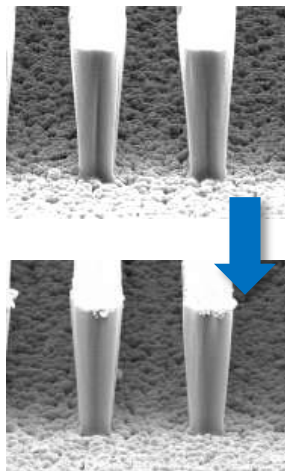
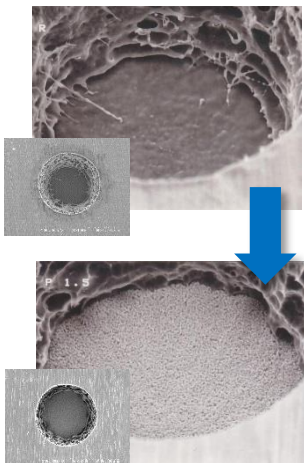
- SAP
- M-SAP

Descum (before Ni/Au)

- Organic residue
- SR surface modification
→ Control UF wettability

Pad cleaning

- Remove oxidized layer
- Control weld wettability



Nissin Plasma Technologies; Desmear

Application

Dry desmear(remove smear after laser drilling process)

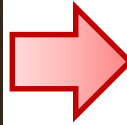
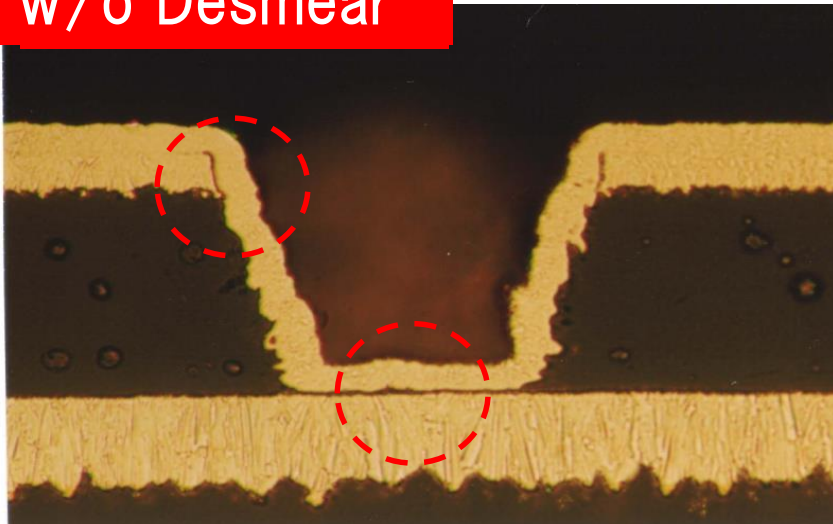
Application example

Process: Desmear for BVH($\phi=100\mu$)

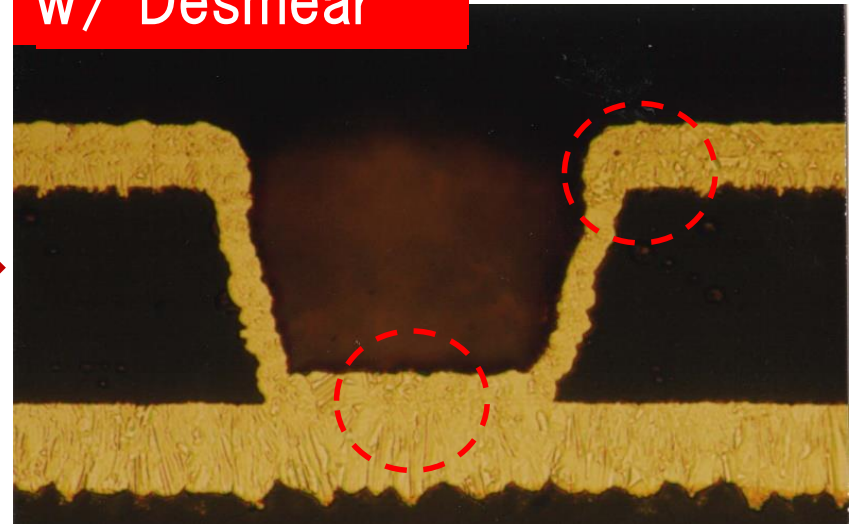
Measurement: Cross-section after Cu plating

Result

w/o Desmear



w/ Desmear



Nissin Plasma Technologies; Desmear

Application

Dry desmear(remove smear after laser drilling process)

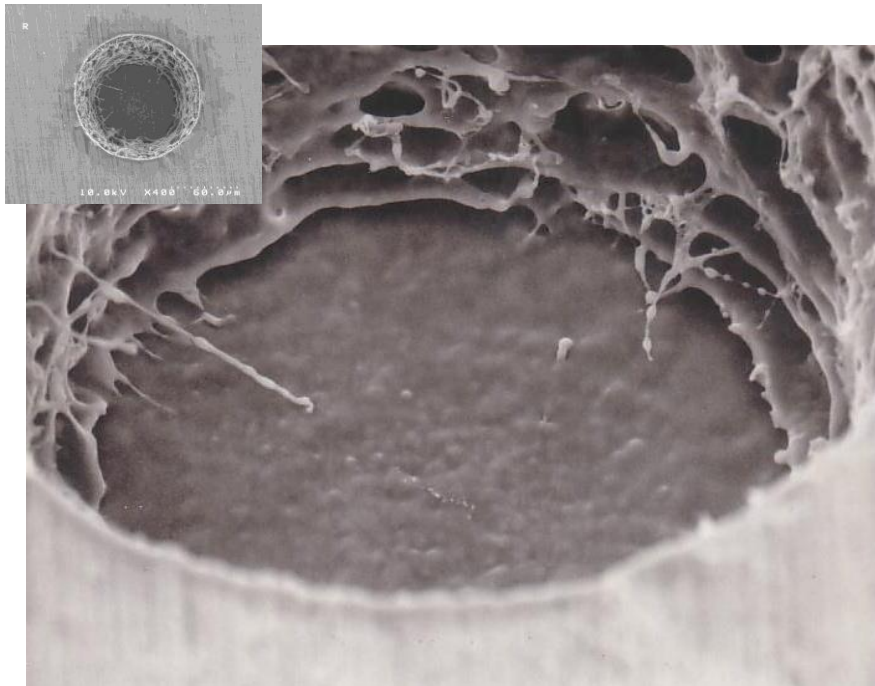
Application example

Process: Desmear for BVH($\phi=100\mu$)

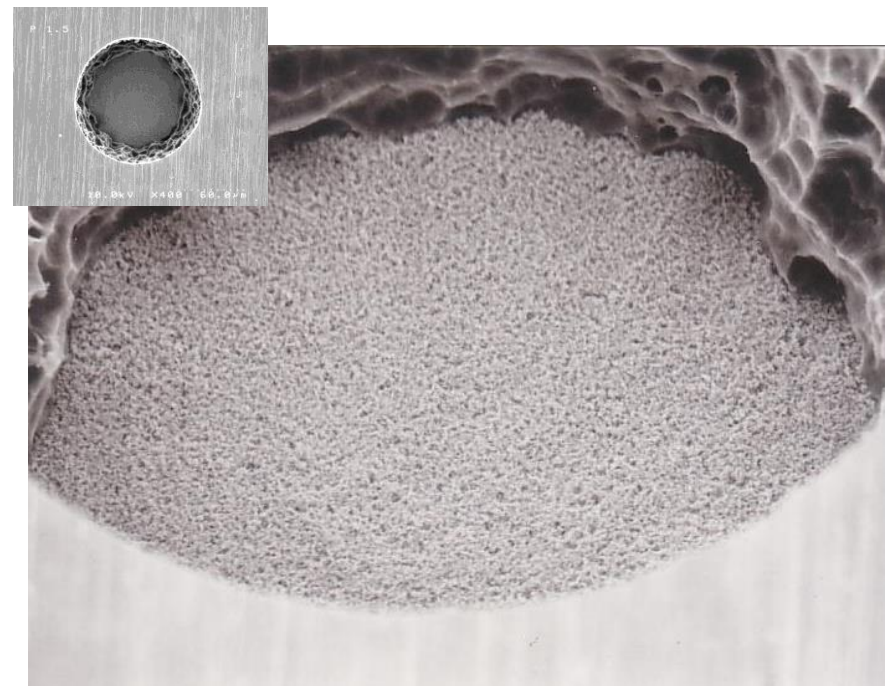
Measurement: SEM

Result

Untreated



Treated



Nissin Plasma Technologies; Desmear

Application

Dry desmear for FPC(remove smear after laser drilling process)

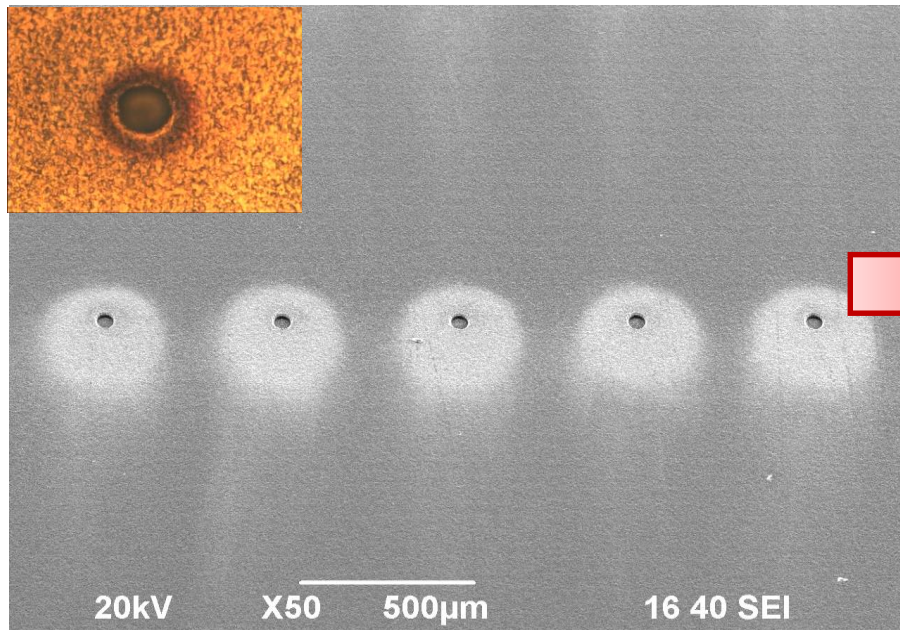
Application example

Process: Desmear for BVH($\phi=50\mu$, Thickness of PI= 25μ , Cu= 12μ)

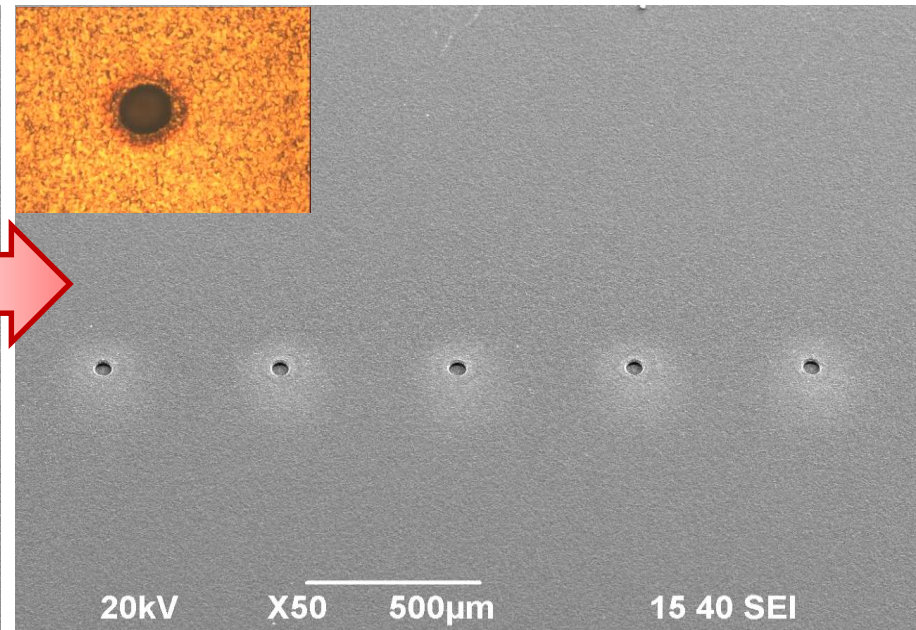
Measurement: Microscope

Result

Untreated



Treated



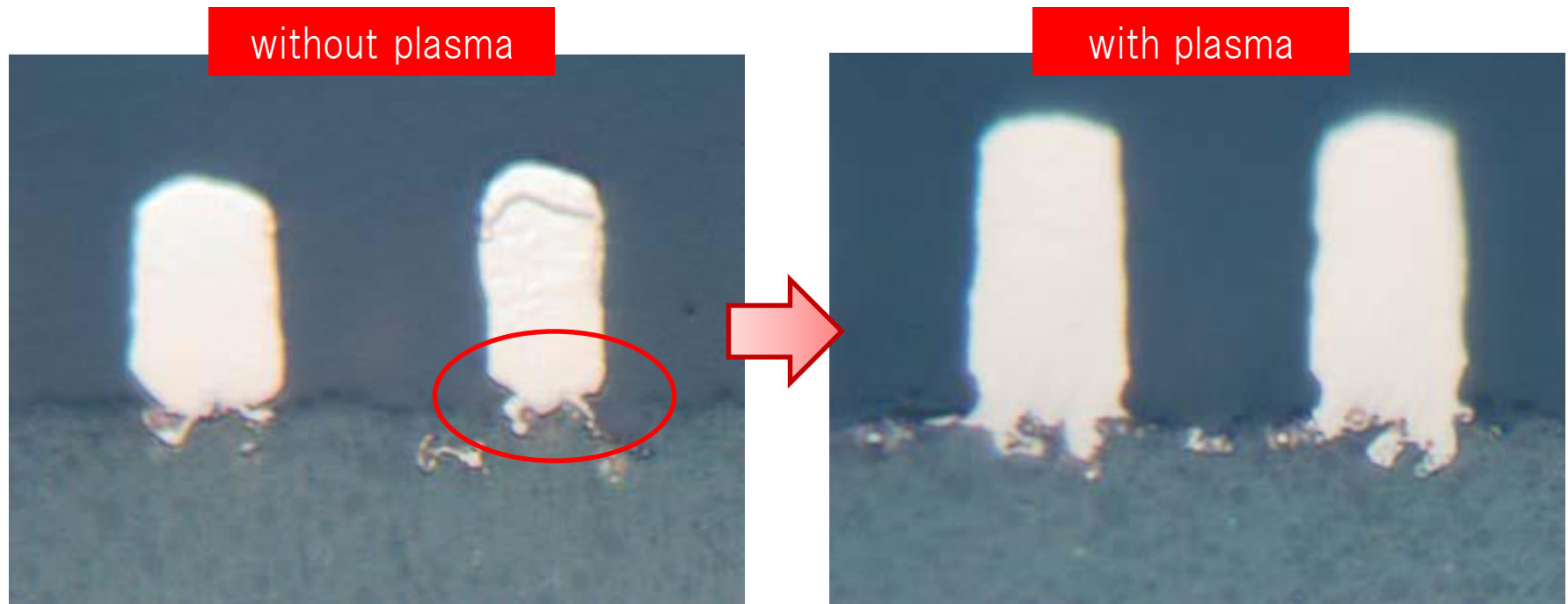
Nissin Plasma Technologies; Descum (SAP)

Application

Remove residue from the bottom of DFR pattern ($\times 2500$ SEM)

L/S : $9/12 \mu\text{m}$

Resist Thickness : $25 \mu\text{m}$

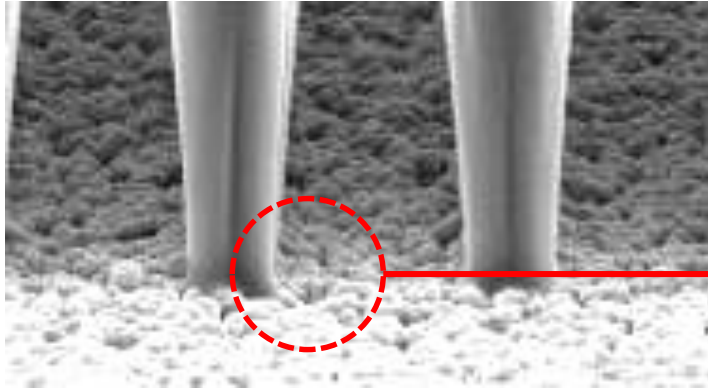


Nissin Plasma Technologies; Descum (SAP)

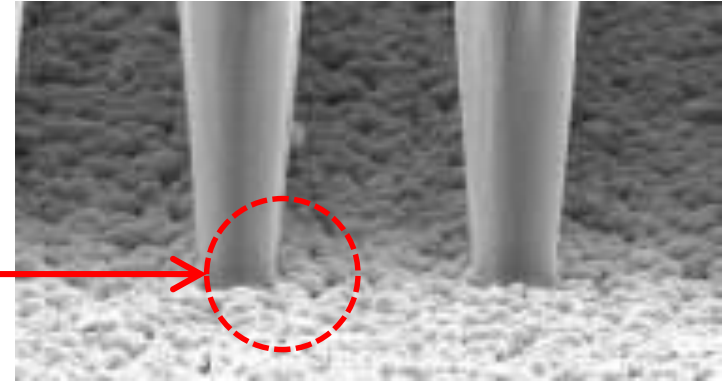
Application

Remove residue from the bottom of DFR pattern $L/S=10/10\mu$ ($\times 2500$ SEM)

Untreated



Treated



Prevent Cu plating failure ($\times 1000$ microscope)

Untreated



Treated



Nissin Plasma Technologies; Descum for Cu pad

Application

Improve wettability by removing micro residue on the surface of plated Cu pad

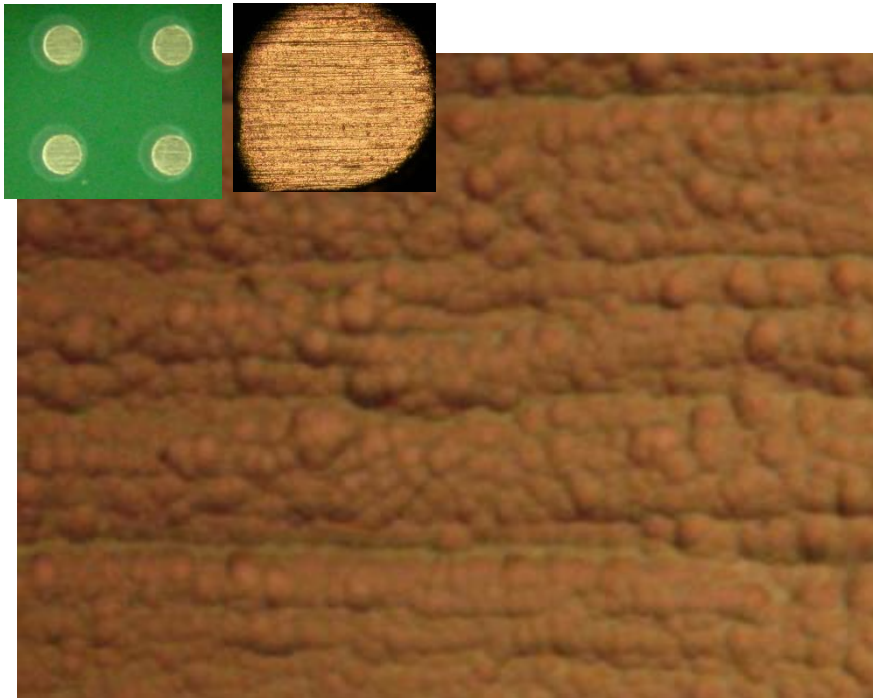
Application example

Process: Descum before Ni/Au plating

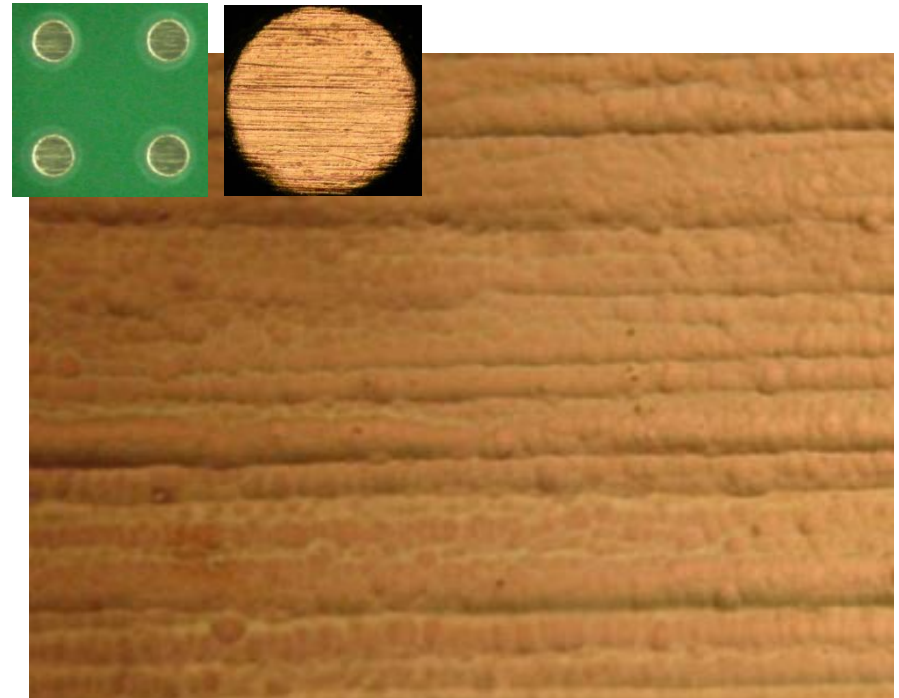
Measurement: Microscope

Result

Untreated



Treated



Nissin Plasma Equipment

Nissin Plasma Equipment ; Line-up

Sheet-by-sheet type
M120-W



Roll to roll type
M120-RTR



Wafer-level type
Micro-Labo PS II

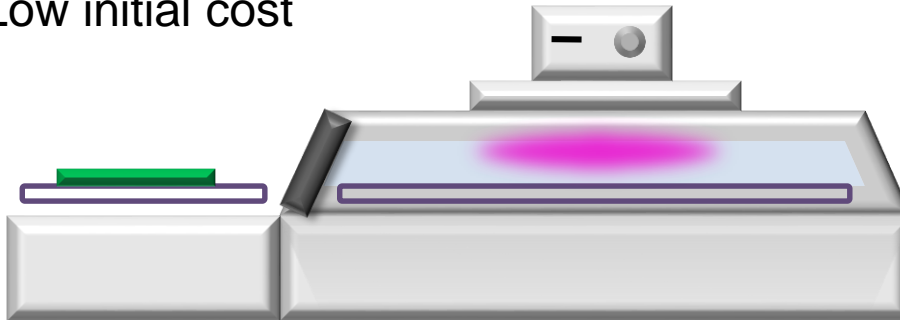


For mass production	For mass production	For small production, R&D
PKG, COF, HDI	COF, Ultra-thin film, Fuel cell	SMT Backend, PKG, R&D
630mm × 640mm	Width: 540mm Outer diameter: ϕ 500mm	120mm × 100mm
Double-sided	Double-sided	Single-sided
Scanning process	Scanning process	Terminate process
Full automation available	Roll to roll available	Full-automation available

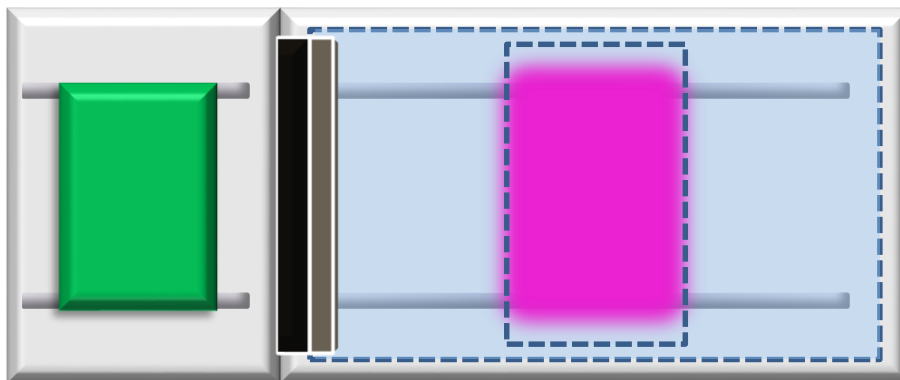
Process flow

Feature

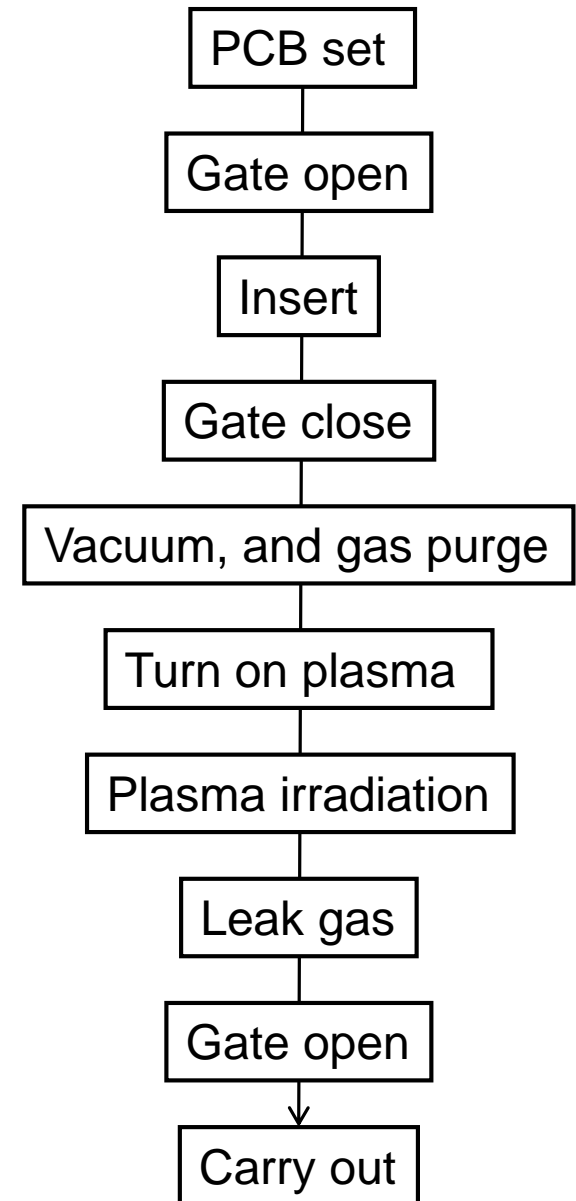
- Return type process
- Single-sided process
- Small footprint
- For small production use
- Low initial cost



Cross-section



Upper view



Specification

- Feature : Sheet by sheet type
For mass production
- Working area : 630mm × 640mm
- Size : 1730(W) × 2530(D) × 2000(H)mm
- Weight : 1500kg
- Processing type : Double-sided
wafer-level processing



M120-W + Handling; Full-automation system image





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